RELIABILITY REPORT

FOR

MAX12931

PLASTIC ENCAPSULATED DEVICES

December 5, 2016

MAXIM INTEGRATED

160 RIO ROBLES

SAN JOSE, CA 95134

Approved by
Eric Wright
Quality Assurance
Reliability Engineer

Conclusion

The MAX12931 successfully meets the quality and reliability standards required of all Maxim Integrated products. In addition, Maxim Integrated's continuous reliability monitoring program ensures that all outgoing product will continue to meet Maxim Integrated's quality and reliability standards.

Table of Contents

I. .....Device Description
II. .....Manufacturing Information
III. .....Packaging Information
.....Attachments
IV. .....Die Information
V. .....Quality Assurance Information
VI. .....Reliability Evaluation

I. Device Description

A. General

The MAX12930/MAX12931 are a family of 2-channel, 3.75kV/5kVRMS digital galvanic isolators using Maximâ€™s proprietary process technology. These devices transfer digital signals between circuits with different power domains while using as little as 0.65mW per channel at 1Mbps with 1.8V.

The two channels of the MAX12931 transfer data in opposite directions, and this makes the MAX12931 ideal for isolating the TX and RX lines of a transceiver. The MAX12930 features two channels transferring data in the same direction.

Both devices are available with a maximum data rate of either 25Mbps or 150Mbps and with the default outputs that are either high or low. The default is the state the output assumes when the input is not powered, or if the input is open-circuit. See the Ordering Information for suffixes associated with each option. Independent 1.71V to 5.5V supplies on each side of the isolator also make the devices suitable for use as level translators.

The MAX12930/MAX12931 are available in an 8-pin, narrow-body SOIC package. In addition, the MAX12931 is available in a 16-pin, wide-body SOIC package. The package material has a minimum comparative tracking index (CTI) of 600V, which gives it a group 1 rating in creepage tables. All devices are rated for operation at ambient temperatures of -40°C to +125°C.

II. Manufacturing Information

A. Description/Function:	Two-Channel Digital Isolators
B. Process:	S18
C. Fabrication Location:	USA
D. Assembly Location:	Taiwan
E. Date of Initial Production:	June 24, 2016

III. Packaging Information

A. Package Type:	16-pin SOIC Hybrid
B. Lead Frame:	Copper
C. Lead Finish:	100% Matte Sn
D. Die Attach:	Conductive
E. Bondwire:	Au (1 mil dia.)
F. Mold Material:	Epoxy with silica filler
G. Assembly Diagram:	#05-100211
H. Flammability Rating:	Class UL94-V0
I. Classification of Moisture Sensitivity per JEDEC standard J-STD-020-C	Level 1
J. Single Layer Theta Ja:	N/A°C/W
K. Single Layer Theta Jc:	N/A°C/W
L. Multi Layer Theta Ja:	71°C/W
M. Multi Layer Theta Jc:	23°C/W

IV. Die Information

A. Passivation:	Si_3N_4/SiO_2 (Silicon nitride/ Silicon dioxide)
B. Interconnect:	Al/0.5%Cu with Ti/TiN Barrier
C. Backside Metallization:	None
D. Minimum Metal Width:	0.23 microns (as drawn)
E. Minimum Metal Spacing:	0.23 microns (as drawn)
F. Isolation Dielectric:	SiO_2
G. Die Separation Method:	Wafer Saw

V. Quality Assurance Information

A. Quality Assurance Contacts:	Eric Wright (Reliability Engineering) Bryan Preeshl (Vice President of QA)
B. Outgoing Inspection Level:	0.1% for all electrical parameters guaranteed by the Datasheet. 0.1% for all Visual Defects.
C. Observed Outgoing Defect Rate:	< 50 ppm
D. Sampling Plan:	Mil-Std-105D

VI. Reliability Evaluation

A. Accelerated Life Test

The results of the 135C biased (static) life test are shown in Table 1. Using these results, the Failure Rate (λ) is calculated as follows:

$$\lambda = \frac{1}{MTTF} = \frac{1.83}{192 \times 4340 \times 80 \times 2}$$ (Chi square value for MTTF upper limit)

(where 4340 = Temperature Acceleration factor assuming an activation energy of 0.8eV)

$\lambda = 13.7 \times 10^{-9}$

$\lambda = 13.7$ F.I.T. (60% confidence level @ 25°C)

The following failure rate represents data collected from Maxim Integrated's reliability monitor program. Maxim Integrated performs quarterly life test monitors on its processes. This data is published in the Reliability Report found at http://www.maximintegrated.com/qa/reliability/monitor. Cumulative monitor data for the S18 Process results in a FIT Rate of 0.06@ 25C and 0.93@ 55C (0.8 eV, 60% UCL)

B. E.S.D. and Latch-Up Testing

The RV25-0 die type has been found to have all pins able to withstand a HBM transient pulse of +/-2500V per JEDEC JESD22-A114. Latch-Up testing has shown that this device withstands a current of +/-250mA and overvoltage per JEDEC JESD78.

Table 1
Reliability Evaluation Test Results

MAX12931

TEST ITEM	TEST CONDITION	FAILURE IDENTIFICATION	SAMPLE SIZE	NUMBER OF FAILURES	COMMENT
Static Life Test (Note 1)					
	Ta = 135C Biased Time = 192 hrs.	DC Parameters & functionality	80	0	

Note 1: Life Test Data may represent plastic DIP qualification lots.